Maplesemi

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Pb
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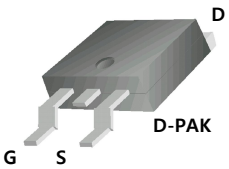
SLD50N06T
60V N-Channel MOSFET

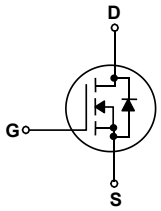
General Description

This Power MOSFET is produced using Maple semi's advanced planar stripe DMOS technology.
This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for low voltage applications such as DC/DC converters and high efficiency switching for power management in portable and battery operated products.

Features

- 50A, 60V, $R_{DS(on)Typ}$ = 18mΩ@V_{GS} = 10 V
- Low gate charge (typical 33nC)
- High ruggedness
- Fast switching
- 100% avalanche tested
- Improved dv/dt capability





Absolute Maximum Ratings

T_C = 25°C unless otherwise noted

Symbol	Parameter		SLD50N06T	Units
V_{DSS}	Drain-Source Voltage		60	V
I_D	Drain Current - Continuous (T_C = 25℃)		50	A
	- Continuous (T_C = 100℃)		30	A
I_{DM}	Drain Current - Pulsed	(Note 1)	200	A
V_{GSS}	Gate-Source Voltage		±30	V
EAS	Single Pulsed Avalanche Energy	(Note 2)	450	mJ
I_{AR}	Avalanche Current	(Note 1)	50	A
E_{AR}	Repetitive Avalanche Energy	(Note 1)	12	mJ
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	4.5	V/ns
P_D	Power Dissipation (T_C = 25℃)		60	W
	- Derate above 25℃		0.8	W/℃
T_J, T_{STG}	Operating and Storage Temperature Range		-55 to +175	℃
T_L	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		300	℃

* Drain current limited by maximum junction temperature.

Thermal Characteristics

Symbol	Parameter	SLD50N06T	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	2.5	℃/W
$R_{\theta JS}$	Thermal Resistance, Case-to-Sink Typ.		℃/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	62.5	℃/W

Package Marking

Part Number	Top Marking	Package	Packing Method	MOQ	QTY
SLD50N06T	SLD50N06T	D-Pak	Tape & Reel	2500	25000

Electrical Characteristics

T_C = 25°C unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Typ	Max	Units
Off Characteristics						
BV_{DSS}	Drain-Source Breakdown Voltage	V_{GS} = 0 V, I_D = 250 uA	60	--	--	V
$\triangle BV_{DSS}$ / $\triangle T_J$	Breakdown Voltage Temperature Coefficient	I_D = 250 uA, Referenced to 25℃	--	0.06	--	V/℃
I_{DSS}	Zero Gate Voltage Drain Current	V_{DS} = 60 V, V_{GS} = 0 V	--	--	1	uA
		V_{DS} = 48 V, T_C = 150℃	--	--	10	uA
I_{GSSF}	Gate-Body Leakage Current, Forward	V_{GS} = 25 V, V_{DS} = 0 V	--	--	100	nA
I_{GSSR}	Gate-Body Leakage Current, Reverse	V_{GS} = -25 V, V_{DS} = 0 V	--	--	-100	nA
On Characteristics						
$V_{GS(th)}$	Gate Threshold Voltage	V_{DS} = V_{GS}, I_D = 250 uA	2.0	--	4.0	V
$R_{DS(on)}$	Static Drain-Source On-Resistance	V_{GS} = 10 V, I_D = 25 A	--	18	22	mΩ
g_{FS}	Forward Transconductance	V_{DS} = 25 V, I_D = 25 A (Note 4)	--	22	--	S
Dynamic Characteristics						
C_{iss}	Input Capacitance	V_{DS} = 25 V, V_{GS} = 0 V, f = 1.0 MHz	--	1300	--	pF
C_{oss}	Output Capacitance		--	520	--	pF
C_{rss}	Reverse Transfer Capacitance		--	75	--	pF
Switching Characteristics						
$t_{d(on)}$	Turn-On Delay Time	V_{DD} = 30 V, I_D = 25 A, R_G = 25 Ω (Note 4, 5)	--	15	--	ns
t_r	Turn-On Rise Time		--	105	--	ns
$t_{d(off)}$	Turn-Off Delay Time		--	60	--	ns
t_f	Turn-Off Fall Time		--	65	--	ns
Q_g	Total Gate Charge	V_{DS} = 48 V, I_D = 50 A, V_{GS} = 10 V (Note 4, 5)	--	33	--	nC
Q_{gs}	Gate-Source Charge		--	8.5	--	nC
Q_{gd}	Gate-Drain Charge		--	14	--	nC
Drain-Source Diode Characteristics and Maximum Ratings						
I_S	Maximum Continuous Drain-Source Diode Forward Current		--	--	50	A
I_{SM}	Maximum Pulsed Drain-Source Diode Forward Current		--	--	200	A
V_{SD}	Drain-Source Diode Forward Voltage	V_{GS} = 0 V, I_S = 50 A	--	--	1.4	V
t_{rr}	Reverse Recovery Time	V_{GS} = 0 V, I_S = 50 A, dI_F / dt = 100 A/us (Note 4)	--	60	--	ns
Q_{rr}	Reverse Recovery Charge		--	80	--	nC

Notes:
1. Repetitive Rating : Pulse width limited by maximum junction temperature
2. I_{AS} = 50A, V_{DD} = 50V, R_G = 25Ω, Starting T_J = 25°C
3. I_{SD} ≤ 50A, di/dt ≤ 200A/us, V_{DD} ≤ BV_{DSS}, Starting T_J = 25°C
4. Pulse Test : Pulse width ≤ 300us, Duty cycle ≤ 2%
5. Essentially independent of operating temperature

Typical Characteristics

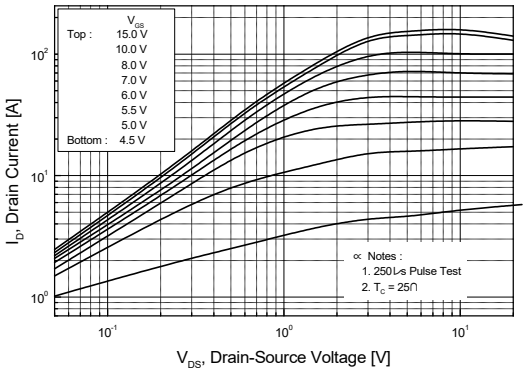


Figure 1. On-Region Characteristics

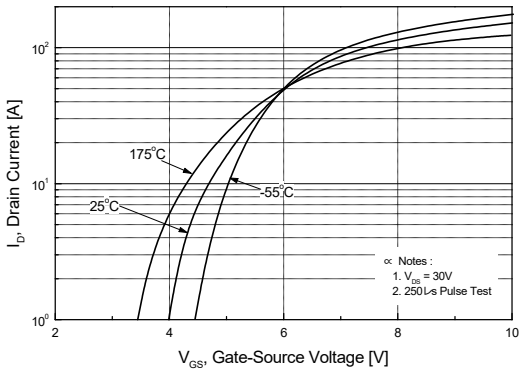


Figure 2. Transfer Characteristics

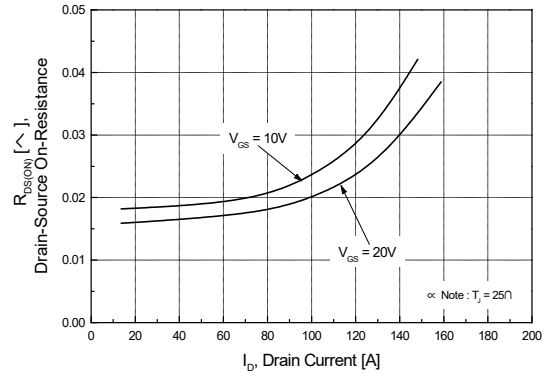


Figure 3. On-Resistance Variation vs Drain Current and Gate Voltage

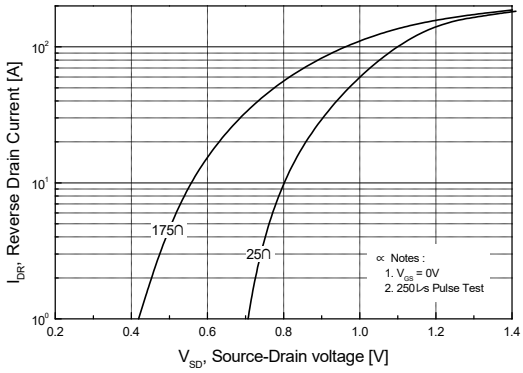


Figure 4. Body Diode Forward Voltage Variation with Source Current and Temperature

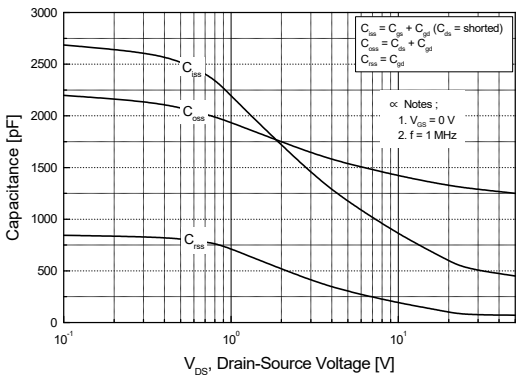


Figure 5. Capacitance Characteristics

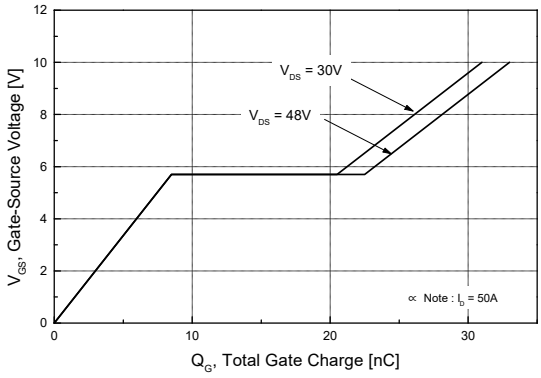


Figure 6. Gate Charge Characteristics

Typical Characteristics (Continued)

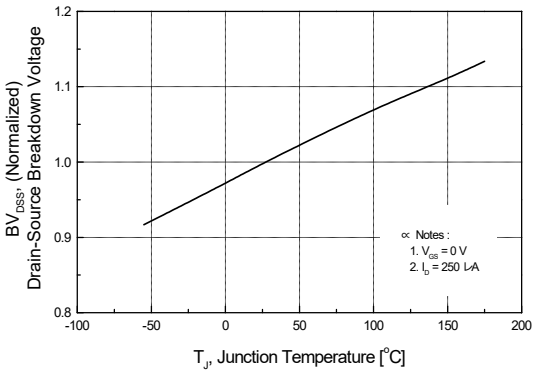


Figure 7. Breakdown Voltage Variation vs Temperature

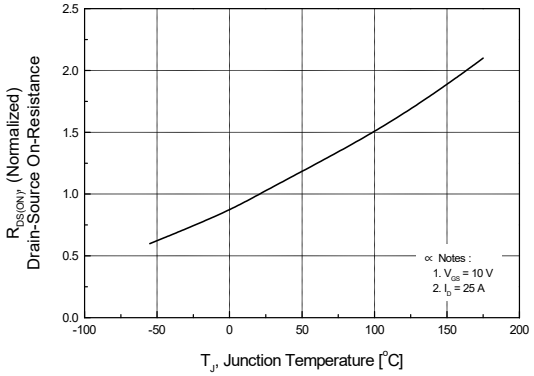


Figure 8. On-Resistance Variation vs Temperature

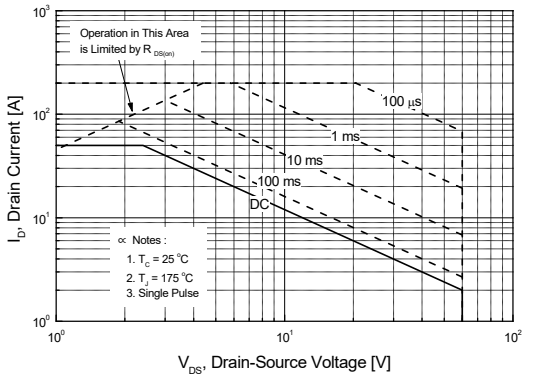


Figure 9. Maximum Safe Operating Area

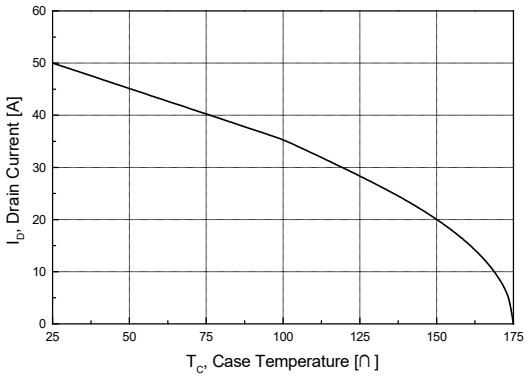


Figure 10. Maximum Drain Current vs Case Temperature

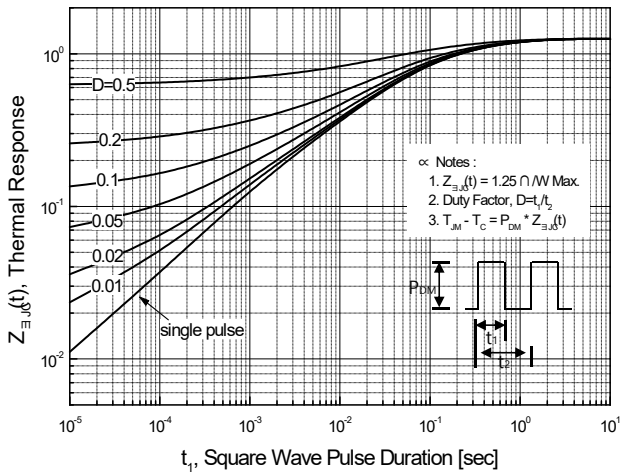
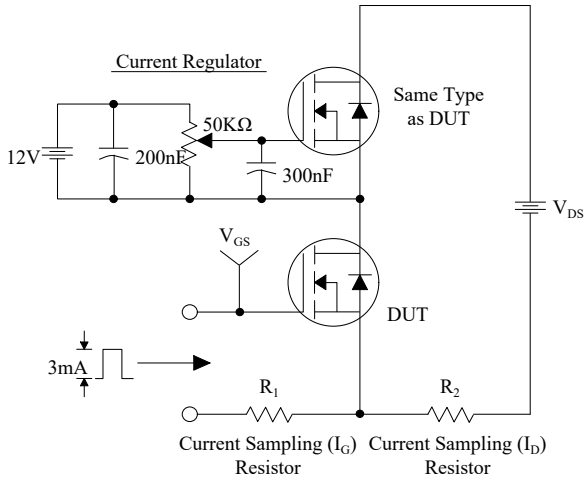
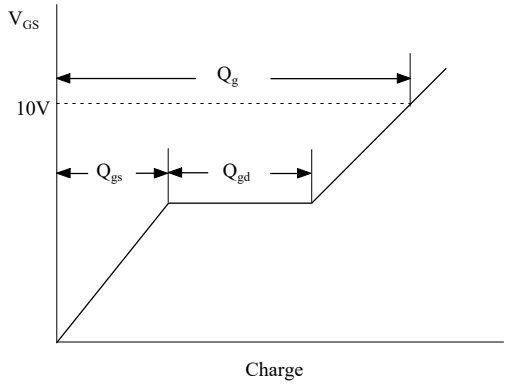


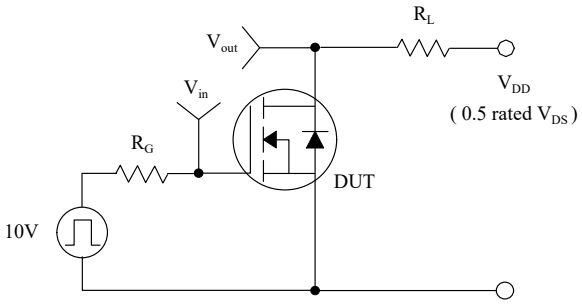
Figure 11-1. Transient Thermal Response Curve

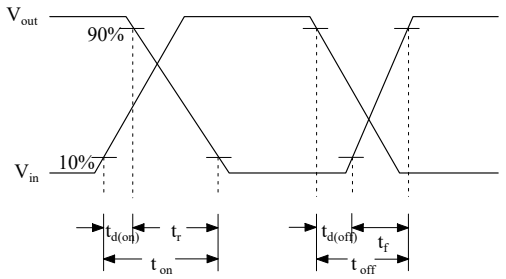
Gate Charge Test Circuit & Waveform



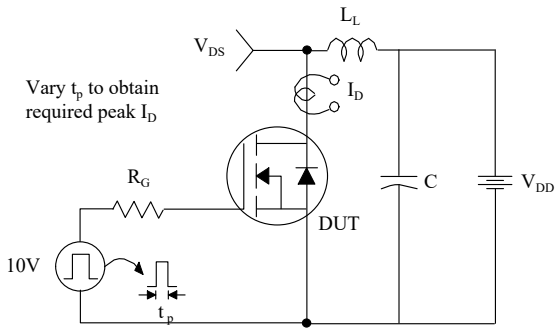


Resistive Switching Test Circuit & Waveforms

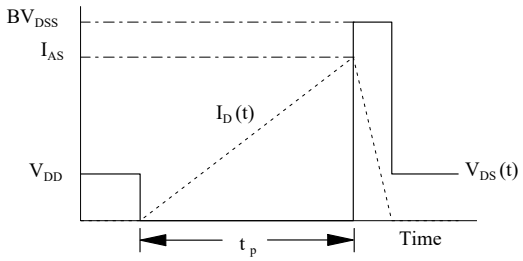




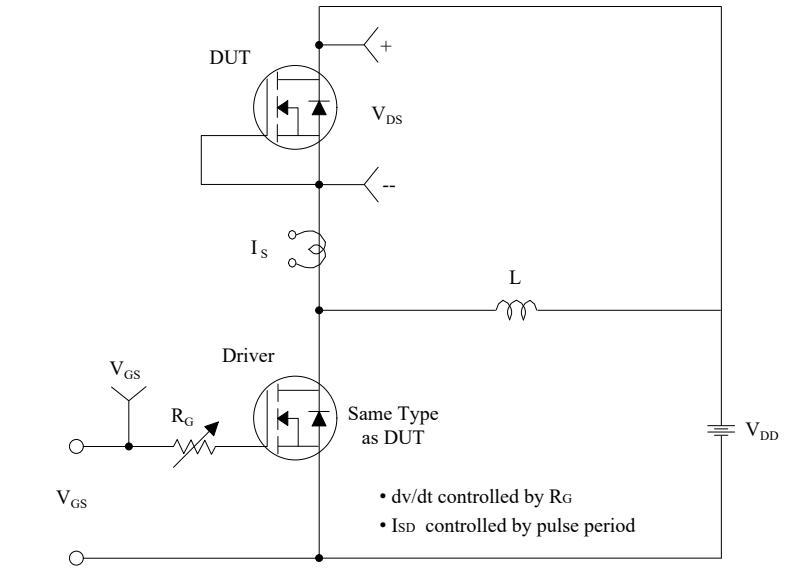
Unclamped Inductive Switching Test Circuit & Waveforms

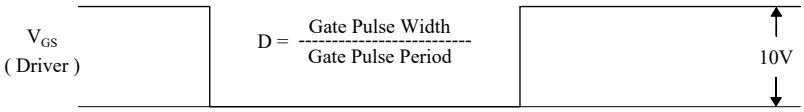


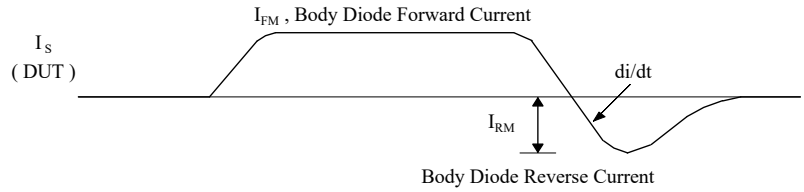
$$E_{AS} = \frac{1}{2} L_L I_{AS}^2 \frac{BV_{DSS}}{BV_{DSS} - V_{DD}}$$

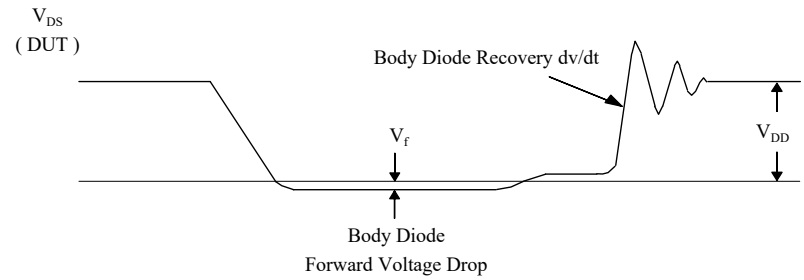


Peak Diode Recovery dv/dt Test Circuit & Waveforms

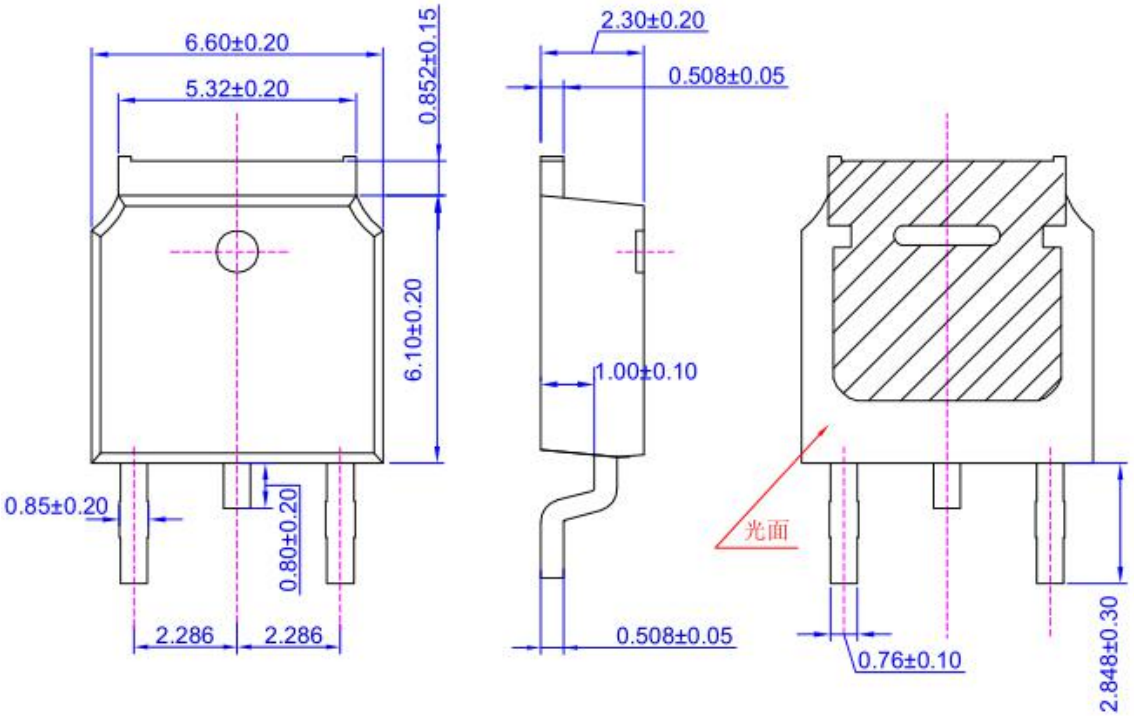


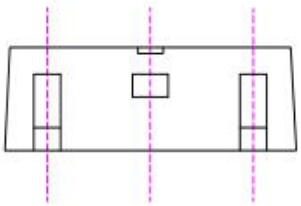






TO-252 OUTLINE





NOTE：
1The plastic package is not marked as smooth surfaceRa=0.1;Subglossy surfaceRa=0.8
2.Undeclared tolerance±0.25,Unmarked filletRmax=0.25

单击下面可查看定价，库存，交付和生命周期等信息

>>Maplesemi(美浦森半导体)